

Search Notes

Application/Control No.

09/757,006

Examiner

Le Nguyen

Applicant(s)/Patent under
Reexamination

GEIER ET AL.

Art Unit

2174

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
consulted w/Vincent Trans	9/14/2006	LVN
consulted w/Tod Swann	9/15/2006	LVN
http://www.netlibrary.com/	9/27/2006	LVN